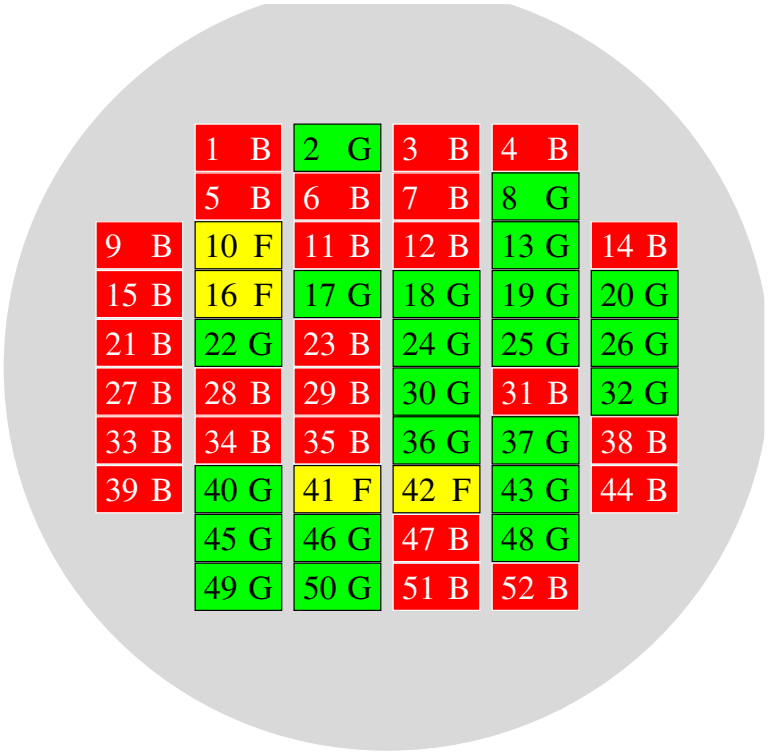
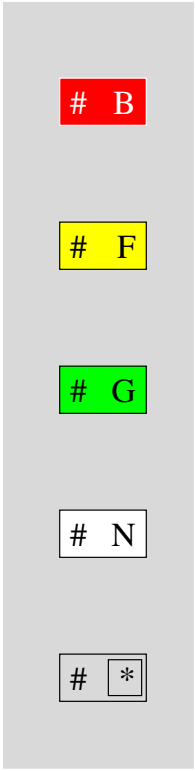
Die quality map for wafer 126 s/n: 21316-04-18

Date: 02/26/99